

Low Latency Signal-Chains for Digital Control Loops with ADS9219



Rahul Kulkarni and Michael Saul

Introduction

Closed-loop systems, such as power-supplies, employ a feedback loop with control logic. The control algorithm can be implemented using either analog or digital circuits. Analog control loops optimize the control feedback for a specific load due to the fixed circuit hardware. In contrast, digital control loops can be optimized for a variety of loads. Furthermore, digital control loops offer higher accuracy because digital control loops are less prone to tolerances in passive components. This article discusses a low-latency control circuit using an analog-to-digital converter (ADC) and digital-to-analog converter (DAC) to implement a digital control loop. Feedback circuits optimized for current and voltage measurement respectively are discussed.

Digital Control Loop

A digital control loop uses an analog-to-digital converter (ADC) for sensing, a processor or FPGA for control and a digital-to-analog converter (DAC) to regulate the output of lab instruments such as power supplies, source measure units, and electronic loads. The main goal of a digital control loop in an instrument is to maintain a stable output voltage or current despite changes in the load conditions or input voltage. The control algorithm can be tuned according to the load to minimize settling time at the output of the instrument.

A typical digital control loop in an instrument includes the following components as shown in [Figure 1](#):

1. Measurement unit: This component measures the output voltage, current, or both, of the instrument and converts the measurement into a digital signal that can be processed by the controller.
2. Controller: The controller receives the digital measurement of the output of the instrument and calculates an error signal, which is the difference between the measured output and the reference signal. The error signal is then processed by the control algorithm to determine the control inputs that need to be applied to the instrument.
3. Control algorithm: This component processes the error signal to determine the control inputs that are applied to the instrument. The control algorithm can be based on a simple proportional-integral-derivative (PID) controller, or a more complex control algorithm such as a linear or nonlinear controller.
4. Digital-to-analog converter (DAC): The DAC is responsible for converting the digital control signals into analog signals that can be applied to the instrument.

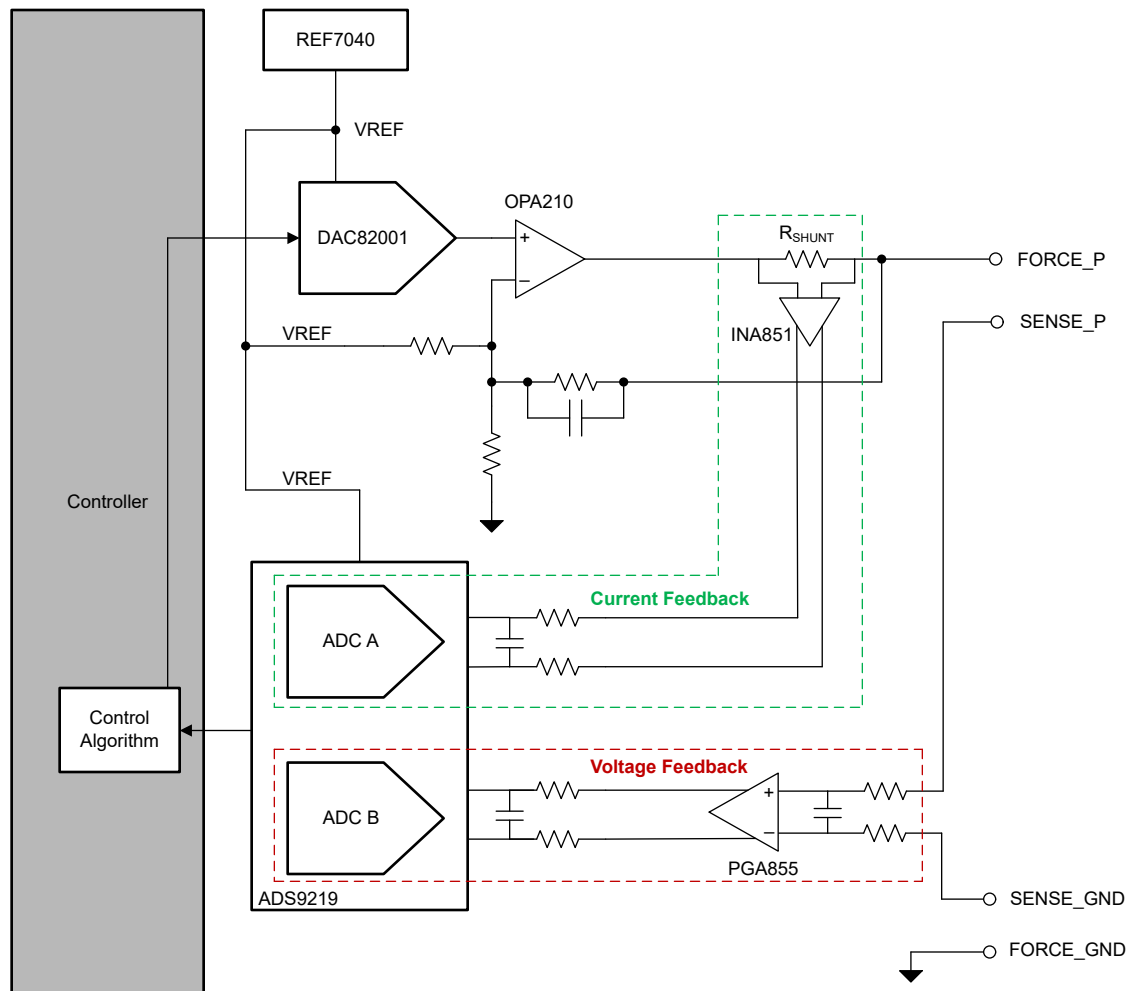


Figure 1. Digital Control Loop Block Diagram

The settling time or response time of the digital control loop depends on the speed at which the control algorithm can adjust the DAC input, to compensate for changes in the output voltage. The total delay in adjusting the DAC output voltage includes the following components:

1. Time required for measuring the output signal in the measurement unit
2. Time required for the control algorithm to generate a new setting for the DAC
3. Time required for the DAC output to settle to required accuracy

To minimize the delay between the input signal and the response of the control loop, a low-latency signal chain to measure current and voltage are needed in the measurement path. The key specifications of the measurement unit signal chains are:

1. DC Accuracy: An accurate measurement unit improves system accuracy because the measurement signal is used to adjust the DAC output signal.
2. Wide Analog Bandwidth: This allows the system to quickly respond to transients in the input signal and changes in the load.

Current Feedback Signal Chain

As shown in [Figure 2](#), the current feedback path consists of a precision shunt resistor, a current sense or instrumentation amplifier, and a low-latency precision analog-to-digital converter.

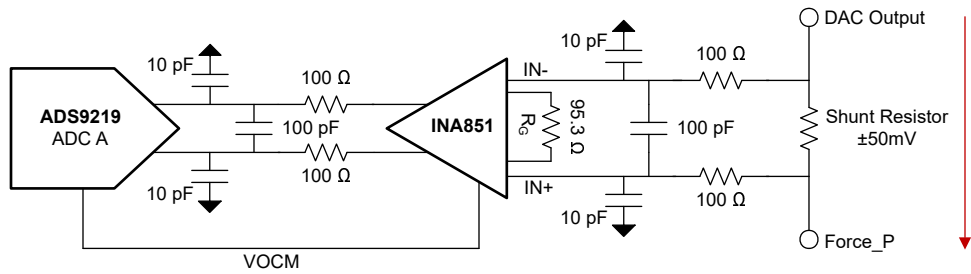


Figure 2. Current Feedback Circuit

The example circuit uses the [INA851](#) and [ADS9219](#). The INA851 is a low-noise, high-speed, instrumentation amplifier with a fully differential output. The DC histogram and step settling plots with oversampling ratios (OSR) of 1 and 16 for this circuit are shown in [Figure 3](#) and [Figure 4](#) respectively.

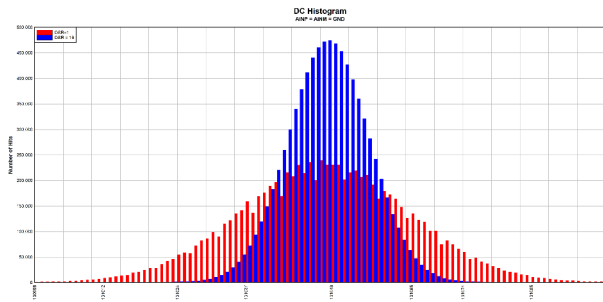


Figure 3. Current Feedback Circuit DC Histogram

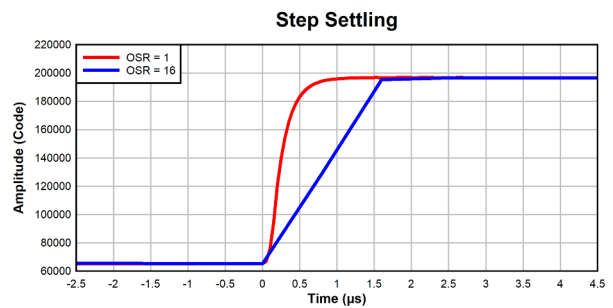


Figure 4. Current Feedback Circuit Step Settling with OSR = 1 and OSR = 16

Table 1. Current Feedback Circuit DC Histogram Results

OSR SETTING	STANDARD DEVIATION	SIGNAL-TO-NOISE RATIO
OSR = 1	14.87LSB	75.89dB
OSR = 16	7.07LSB	82.35dB

Voltage Feedback Signal Chain

As shown in [Figure 5](#), the voltage feedback path consists of a programmable gain amplifier (PGA), and a low-latency precision ADC.

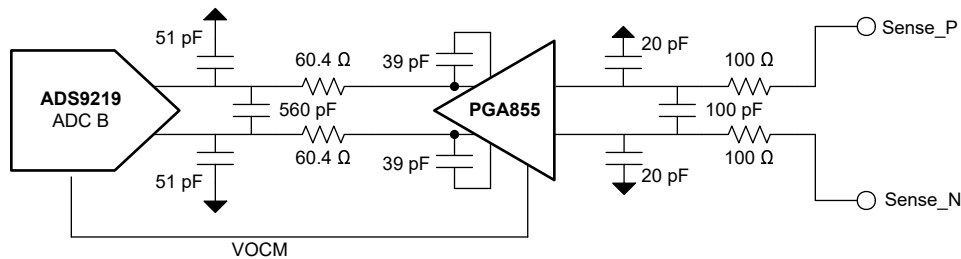


Figure 5. Voltage Feedback Circuit

The example circuit uses [PGA855](#) and [ADS9219](#). The PGA855 is a low-noise, wide-bandwidth, programmable-gain instrumentation amplifier with a fully-differential output. The DC histogram and step settling plots for this circuit are shown in [Figure 6](#) and [Figure 7](#) respectively.

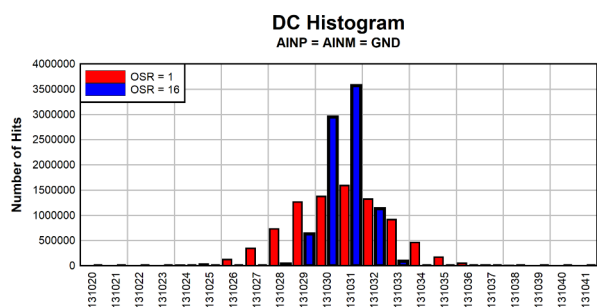


Figure 6. Voltage Feedback Circuit DC Histogram

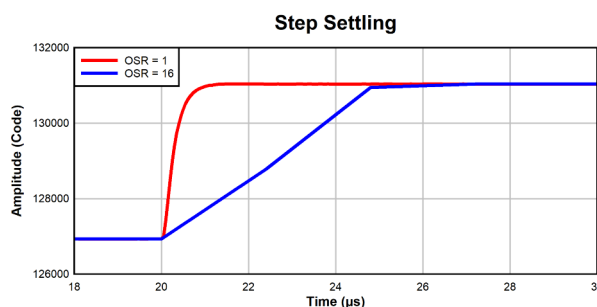


Figure 7. Voltage Feedback Circuit Step Settling

Table 2. Voltage Feedback Circuit DC Histogram Results

OSR SETTING	STANDARD DEVIATION	SIGNAL-TO-NOISE RATIO
OSR = 1	2.08LSB	92.98dB
OSR = 16	0.86LSB	100.6dB

Precision, High-Speed Analog-to-Digital Converter

In the two circuits shown in [Figure 2](#) and [Figure 5](#), [ADS9219](#) is used to accurately and quickly measure the system output signal. By converting the measured analog signal to a digital value at a high speed, the ADC helps to minimize the delay between the input signal and the response of the controller. The low-latency ADC improves the performance of the control loop by allowing the system to respond quickly and accurately to changes in the input signal

The [ADS9219](#) is an 18-bit 20MSPS ADC based on successive approximation register (SAR) architecture that converts an analog signal to a digital value in 50ns. The controller must read the digital value from the ADC and this communication adds an additional time of 50ns. As a result, the controller can get a digital value from the measurement unit based on [ADS9219](#) in a total time of 100ns.

The accuracy of the ADC affects the accuracy of the output of the instrument. The measurement accuracy depends on the thermal drift of errors in the measurement unit and the operating temperature range. The offset and gain errors in the measurement can be calibrated using a calibration circuit after the instrument powers-up to increase accuracy. The 18-bit resolution of [ADS9219](#) enables high-accuracy measurements as shown in [Table 3](#).

Table 3. Measurement Accuracy of ADS9219

CONDITION	INL (ppm)	OFFSET ERROR (ppm)	GAIN ERROR (ppm)	TUE (ppm)	ACCURACY
25°C	3.8	76.3	100	125.8	0.0125%
25°C after calibration	3.8	0	0	3.8	0.0003%
25°C ±5°C after calibration	3.8	5	10	11.81	0.0011%
25°C ±25°C after calibration	3.8	25	50	56.03	0.0056%

Conclusion

Digital control loops are optimized for a variety of different loads and enable higher accuracy systems compared to analog control loops. To enable digital control loops, high accuracy, wide bandwidth signal-chains are needed in the measurement path. [INA851](#) and [PGA855](#) are fully-differential instrumentation amplifiers that can be paired with [ADS9219](#) to implement wide bandwidth, high precision signal-chains in digital control loops.

Trademarks

All trademarks are the property of their respective owners.

IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATA SHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to [TI's Terms of Sale](#) or other applicable terms available either on [ti.com](https://www.ti.com) or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265
Copyright © 2024, Texas Instruments Incorporated